CERTIFY THAT ON SEPTEMBER 5, 2006, WHICH IS THE DATE I AM SIGNING THIS CERTIFICATE, THIS CORRESPONDENCE AND IDENTIFIED ENCLOSURES ARE BEING DEPOSITED IN THE UNITED STATES POSTAL SERVICE, POSTAGE PAID FIRST CLASS, IN AN ENVELOPE ADDRESSED TO: MAIL STOP AMENDMENT, COMMISSIONER FOR PATENTS, P.O. BOX 1450, ALEXANDRIA, VA 22313-1450.

STEVEN W. SMYRSKI

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

YUNG-HO CHUANG, ET AL.

Title: Inspection System Using Small Catadioptric Objective

Serial No.: 10/615,512

Filed: July 7, 2003

Group Art Unit: 2872

Examiner: Lee A. Fineman

SUBMISSION OF INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The Information Disclosure Statement submitted herewith, including completed Form PTO-1449, is being filed after the period specified in 37 C.F.R. § 1.97(b), but before the mailing date of a final action under 37 C.F.R. § 1.113, a notice of allowance under 37 C.F.R. § 1.311, or an action that otherwise closes prosecution in the application.

Atty Docket No. KLAC0075 Page 2

S.N. 10/615,512 Yung-Ho Chuang, et al.

Applicants enclose herewith a check in the amount of \$180.00 in accordance with the fee required in 37 C.F.R. § 1.17(p).

It is believed that no additional fee is due in accordance with this Information Disclosure Statement. If it should be determined for any reason an insufficient fee has been paid, please charge any insufficiency to ensure consideration of the Information Disclosure Statement for the above identified application to Deposit Account 502026.

Respectfully submitted,

Date: September 5, 2006

Steven W. Smyrski, Esq. Registration No. 38,312

SMYRSKI LAW GROUP, A PROFESSIONAL CORPORATION 3310 Airport Avenue, SW Santa Monica, California 90405-6118

Phone: 310.397.9118 Fax: 310.397.9158

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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